

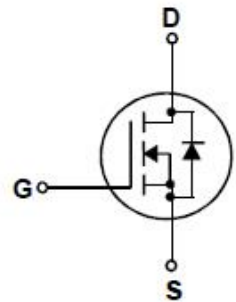
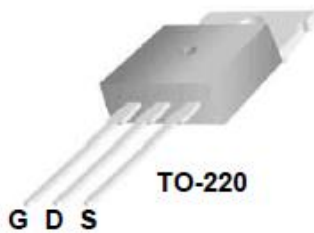
650V N-Channel MOSFET

General Description

This Power MOSFET is produced using advanced planar stripe DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switched mode power supplies, active power factor correction based on half bridge topology.

Features

- 4.5A , 650V, $R_{DS(on)typ.} = 2.3\Omega @ V_{GS} = 10V$
- Low gate charge
- High ruggedness
- Fast switching
- Improved dv/dt capability



Absolute Maximum Ratings $T_c = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter		JFPC5N65C	JFFC5N65C	Units
V _{DSS}	Drain – Source Voltage		650		V
I _D	Drain Current	Continuous (T _C = 25 °C)	4.5	4.5*	A
		Continuous (T _C = 100 °C)	2.7	2.7*	A
I _{DM}	Drain Current - Pulsed (Note 1)		16		A
V _{GSS}	Gate – Source Voltage		±30		V
EAS	Single Pulsed Avalanche Energy (Note 2)		135		mJ
I _{AR}	Avalanche Current (Note 1)		4.5		A
E _{AR}	Repetitive Avalanche Energy (Note 1)		12.65		mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)		4.5		V/ns
P _D	Power Dissipation (T _C = 25 °C)		126	35	W
	-Derate above 25 °C		1.01	0.29	W/°C
T _J ,T _{STG}	Operating and Storage Temperature Range		-55 to +150		°C
T _L	Maximum lead temperature for soldering purposes 1/8” from case for 5 seconds		300		°C

*Drain current limited by maximum junction temperature.

Thermal characteristics

Symbol	Parameter	JFPC5N65C	JFFC5N65C	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.99	3.49	$^{\circ}\text{C}/\text{W}$
$R_{\theta JS}$	Thermal Resistance, Case-to-Sink Typ.	0.5	--	$^{\circ}\text{C}/\text{W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	62.5	$^{\circ}\text{C}/\text{W}$

Electrical Characteristics $T_C = 25^{\circ}\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
Off Characteristics						
BV _{DSS}	Drain – Source Breakdown Voltage	V _{GS} = 0 V, I _D = 250 uA	650	--	--	V
ΔBV _{DSS} /ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 250 uA, Referenced to 25°C	--	0.6	--	V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 650 V, V _{GS} = 0 V	--	--	1	uA
		V _{DS} = 520 V, T _c = 125 °C	--	--	10	uA
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{GS} = 0 V	--	--	100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -30 V, V _{GS} = 0 V	--	--	-100	nA
On Characteristics						
V _{GS(th)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = 250 uA	2.0	--	4.0	V
R _{DS(on)}	Static Drain-Source on-Resistance	V _{GS} = 10V, I _D = 2.25 A	--	2.3	2.5	Ω
g _{FS}	Forward Transconductance	V _{DS} = 40 V, I _D = 2.25 A (Note 4)	--	3.8	--	S
Dynamic Characteristics						
C _{iss}	Input Capacitance	V _{DS} = 25 V, V _{GS} = 0 V, f = 1.0 MHz	--	590	--	pF
C _{oss}	Output Capacitance		--	55	--	pF
C _{rss}	Reverse Transfer Capacitance		--	5	--	pF
Switching Characteristics						
t _{d(on)}	Turn-On Delay Time	V _{DS} = 325 V, I _D = 4.5 A , V _{GS} = 10 V, R _G = 10Ω (Note 4,5)	--	14	--	ns
t _r	Turn-On Rise Time		--	15	--	ns
t _{d(off)}	Turn-Off Delay Time		--	35	--	ns
t _f	Turn-Off Fall Time		--	13	--	ns
Q _g	Total Gate Charge	V _{DS} = 520 V, I _D = 4.5 A V _{GS} = 10 V (Note 4,5)	--	15	--	nC
Q _{gs}	Gate-Source Charge		--	3.0	--	nC
Q _{gd}	Gate-Drain Charge		--	7	--	nC
Drain – Source Diode Characteristics and Maximum Ratings						
I _S	Maximum Continuous Drain-Source Diode Forward Current		--	--	4.5	A
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current		--	--	16	A
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 4.5 A	--	--	1.4	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _S = 4.5 A	--	250	--	ns
Q _{rr}	Reverse Recovery Charge	di _F /dt = 100 A/us (Note 4,5)	--	1.05	--	uC

Notes:

1. Repetitive Rating : Pulsed width limited by maximum junction temperature
2. $L = 10\text{ mH}$, $I_{AS} = 5.0\text{ A}$, $V_{DD} = 50\text{ V}$, $R_G = 25\Omega$, Starting $T_J = 25^{\circ}\text{C}$
3. $I_{SD} \leq 4.5\text{ A}$, $di/dt \leq 100\text{ A}/\mu\text{s}$, $V_{DD} \leq BV_{DSS}$, Starting $T_J = 25^{\circ}\text{C}$
4. Pulsed Test : Pulsed width $\leq 300\mu\text{s}$, Duty cycle $\leq 2\%$
5. Essentially independent of operating temperature

Typical Characteristics

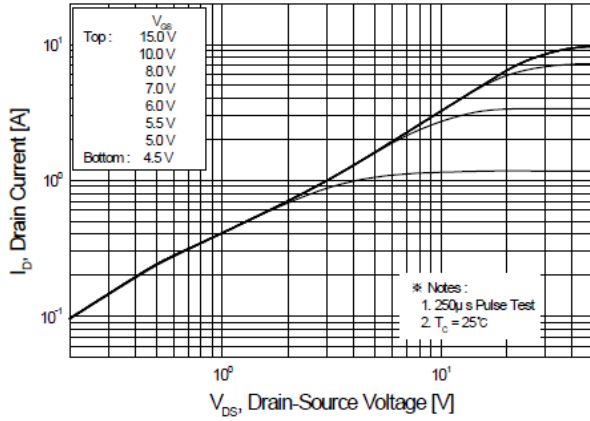


Figure 1. On-Region Characteristics

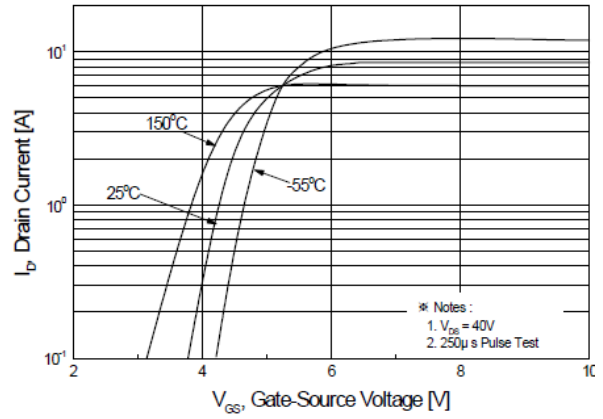


Figure 2. Transfer Characteristics

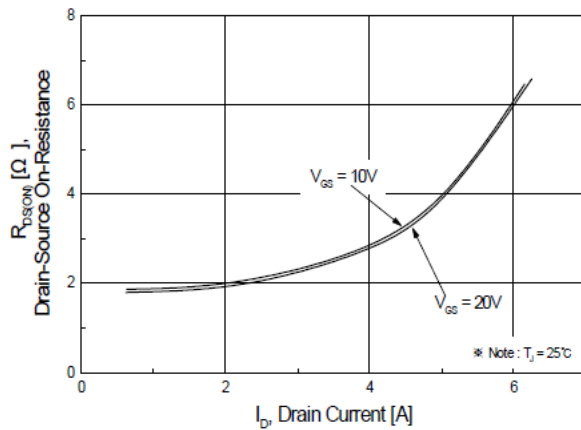


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

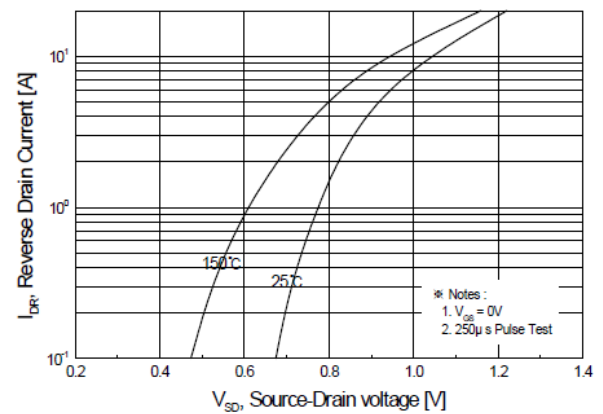


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

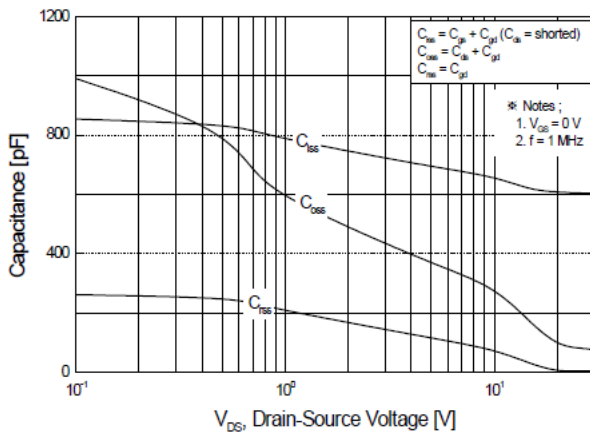


Figure 5. Capacitance Characteristics

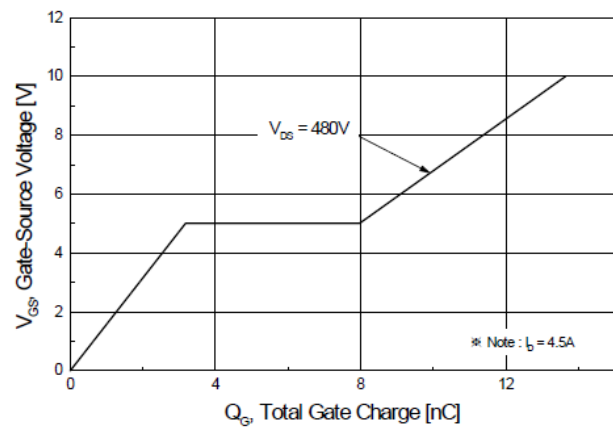


Figure 6. Gate Charge Characteristics

Typical Characteristics

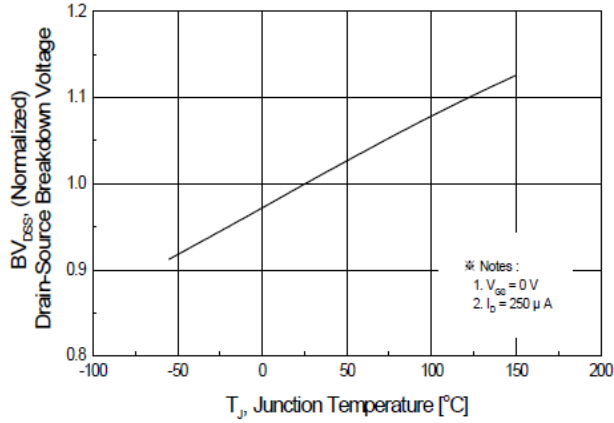


Figure 7. Breakdown Voltage Variation vs Temperature

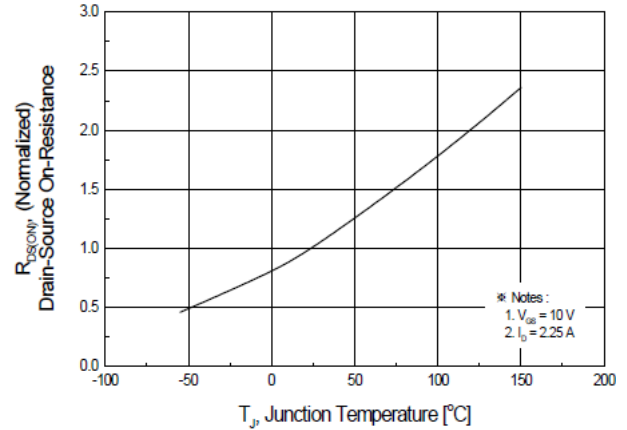


Figure 8. On-Resistance Variation vs Temperature

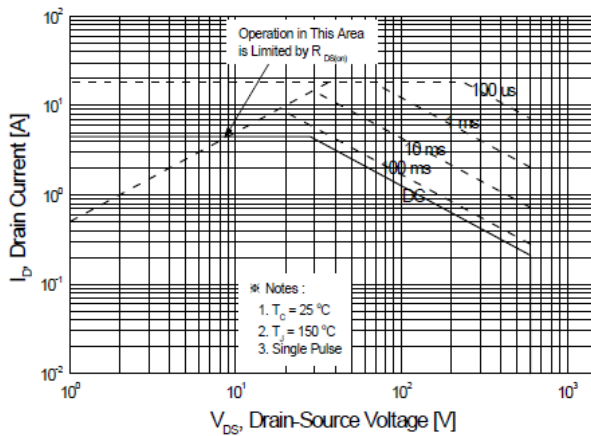


Figure 9-1. Maximum Safe Operating Area for JFPC5N65C

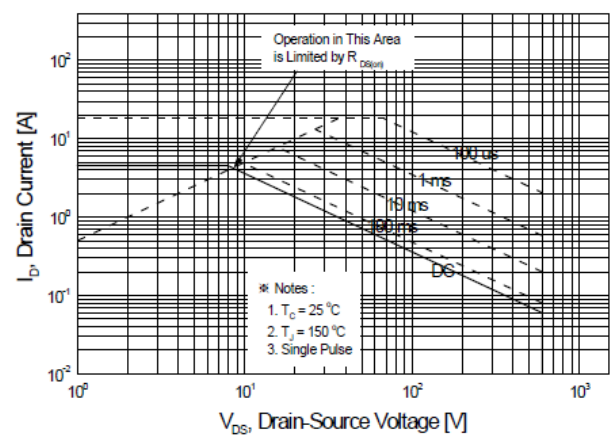


Figure 9-2. Maximum Safe Operating Area for JFFC5N65C

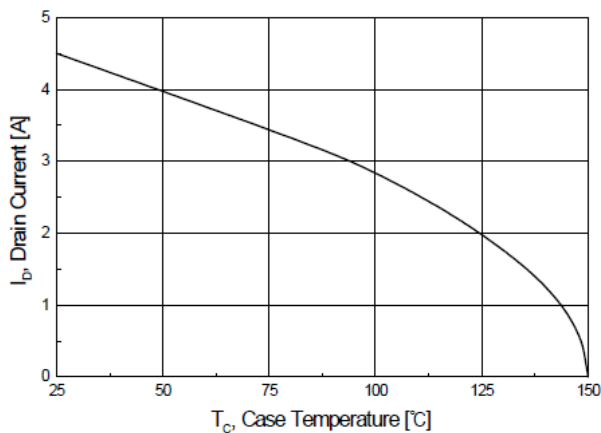


Figure 10. Maximum Drain Current vs Case Temperature

Typical Characteristics

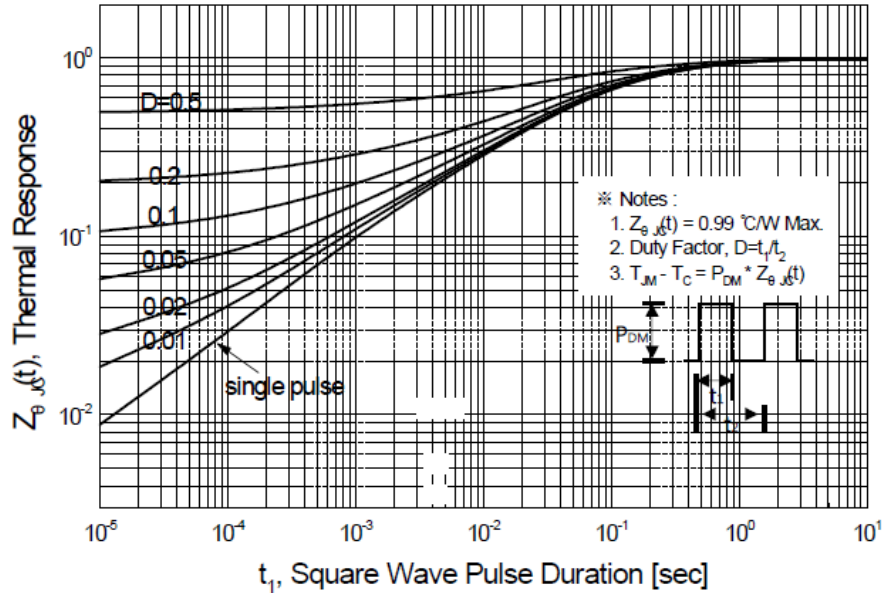


Figure 11-1. Transient Thermal Response Curve for JFPC5N65C

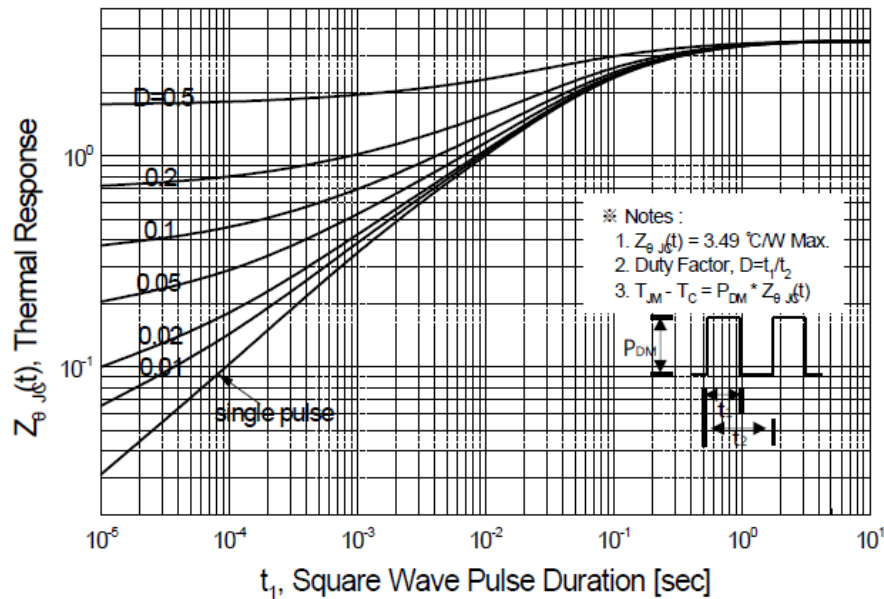
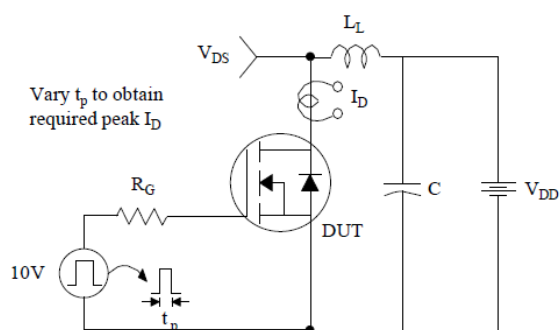
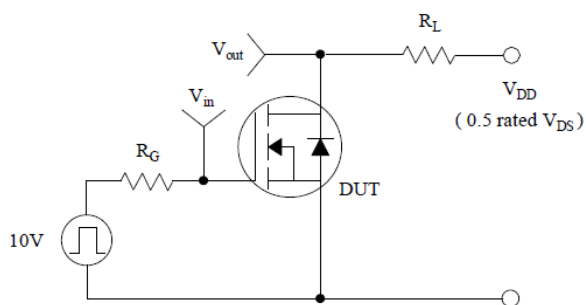


Figure 11-2. Transient Thermal Response Curve for JFFC5N65C

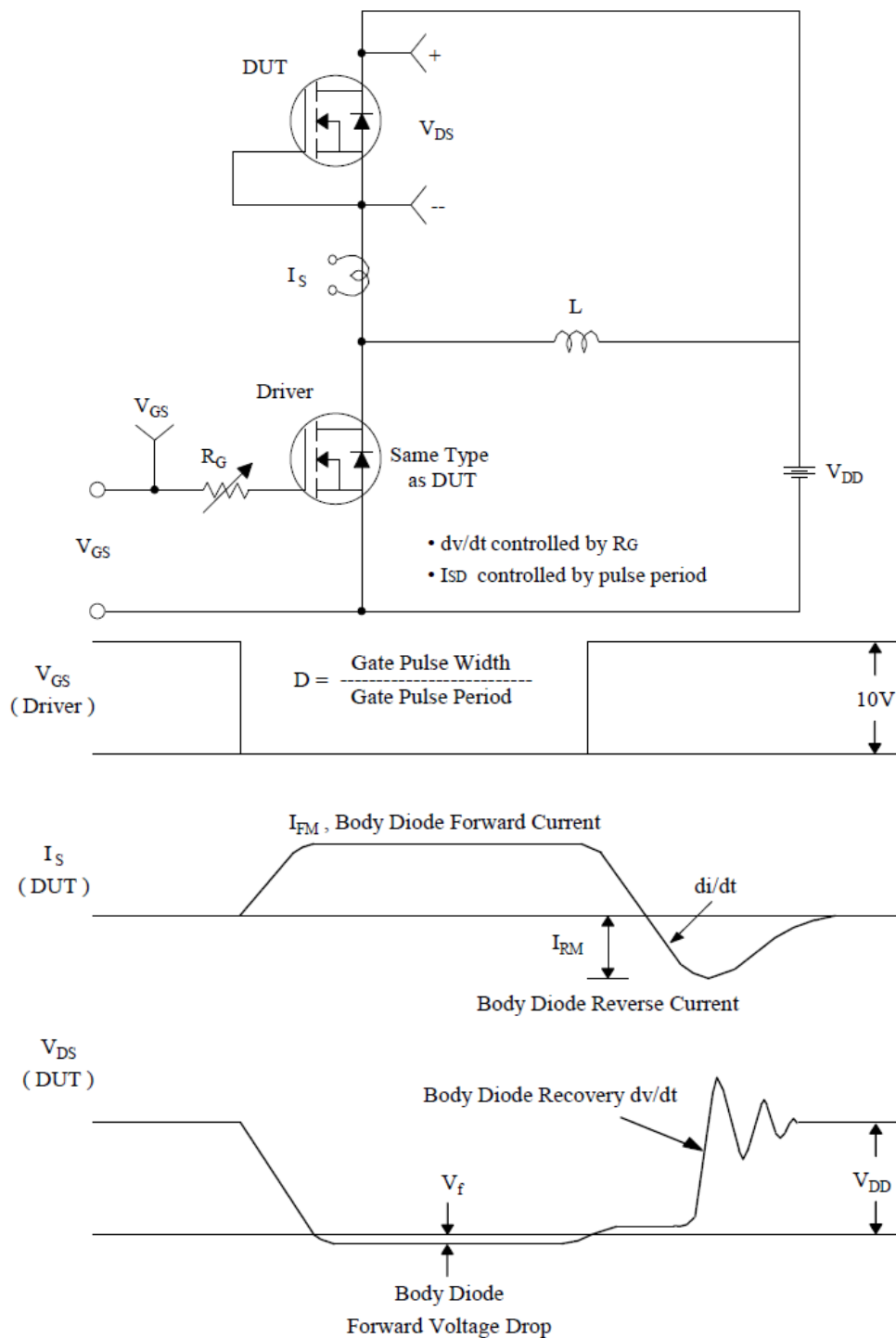
The diagram shows a circuit for measuring the current through a Device Under Test (DUT). A 12V DC source is connected to a current regulator circuit. The current regulator consists of a 200nF capacitor in parallel with a 50KΩ resistor. The output of the current regulator is connected to the DUT. The DUT is represented by a symbol labeled "DUT". The current through the DUT is measured using two current sampling resistors, R_1 and R_2 , which are connected in series with the DUT. The voltage across R_1 is labeled V_{GS} . The current through R_1 is labeled I_G (Current Sampling I_G Resistor). The current through R_2 is labeled I_D (Current Sampling I_D Resistor). A 3mA current source is connected to the input of the current regulator. A 300nF capacitor is connected in parallel with the DUT. The output voltage of the DUT is labeled V_{DS} .



$$E_{AS} = \frac{1}{2} L_L I_{AS}^2 \frac{BV_{DSS}}{BV_{DSS} - V_{DD}}$$

The graph shows the drain current $I_D(t)$ and drain-source voltage $V_{DS}(t)$ versus time. The drain current $I_D(t)$ is zero until t_p , then rises linearly to I_{AS} , and then falls linearly to zero. The drain-source voltage $V_{DS}(t)$ is V_{DD} until t_p , then rises linearly to BV_{DSS} , and then falls linearly to zero. The peak current I_{AS} and peak voltage BV_{DSS} are indicated by dashed lines.

Test Circuit & Waveform



Peak Diode Recovery dv/dt Test Circuit & Waveforms